Lattice Semiconductor Corporation - LC4128ZE-5TN100C Datasheet

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Understanding Embedded - CPLDs (Complex Programmable Logic Devices)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details	
Product Status	Active
Programmable Type	In System Programmable
Delay Time tpd(1) Max	5.8 ns
Voltage Supply - Internal	1.7V ~ 1.9V
Number of Logic Elements/Blocks	8
Number of Macrocells	128
Number of Gates	-
Number of I/O	64
Operating Temperature	0°C ~ 90°C (TJ)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lc4128ze-5tn100c

Product Term Allocator

The product term allocator assigns product terms from a cluster to either logic or control applications as required by the design being implemented. Product terms that are used as logic are steered into a 5-input OR gate associated with the cluster. Product terms that used for control are steered either to the macrocell or I/O cell associated with the cluster. Table 2 shows the available functions for each of the five product terms in the cluster.

Table 2. Individual PT Steering

Product Term	Logic	Control
PT*n*	Logic PT	Single PT for XOR/OR
PT*n*+1	Logic PT	Individual Clock (PT Clock)
PT*n*+2	Logic PT	Individual Initialization or Individual Clock Enable (PT Initialization/CE)
PT*n*+3	Logic PT	Individual Initialization (PT Initialization)
PT*n*+4	Logic PT	Individual OE (PTOE)

Cluster Allocator

The cluster allocator allows clusters to be steered to neighboring macrocells, thus allowing the creation of functions with more product terms. Table 3 shows which clusters can be steered to which macrocells. Used in this manner, the cluster allocator can be used to form functions of up to 20 product terms. Additionally, the cluster allocator accepts inputs from the wide steering logic. Using these inputs, functions up to 80 product terms can be created.

Table 3. Available Clusters for Each Macrocell

Macrocell	Available Clusters			
M0	—	C0	C1	C2
M1	C0	C1	C2	C3
M2	C1	C2	C3	C4
M3	C2	C3	C4	C5
M4	C3	C4	C5	C6
M5	C4	C5	C6	C7
M6	C5	C6	C7	C8
M7	C6	C7	C8	C9
M8	C7	C8	C9	C10
M9	C8	C9	C10	C11
M10	C9	C10	C11	C12
M11	C10	C11	C12	C13
M12	C11	C12	C13	C14
M13	C12	C13	C14	C15
M14	C13	C14	C15	—
M15	C14	C15	—	—

Wide Steering Logic

The wide steering logic allows the output of the cluster allocator n to be connected to the input of the cluster allocator *n*+4. Thus, cluster chains can be formed with up to 80 product terms, supporting wide product term functions and allowing performance to be increased through a single GLB implementation. Table 4 shows the product term chains.

Table 4. Product Term Expansion Capability

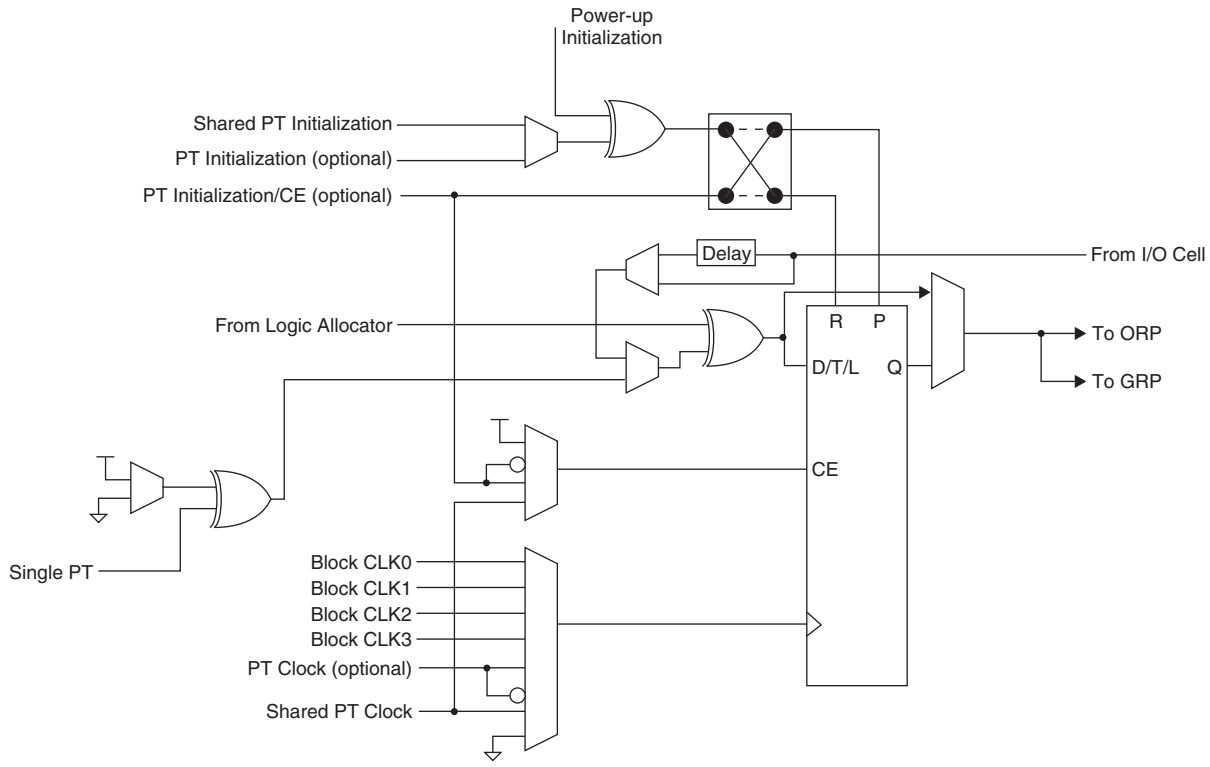
Expansion Chains	Macrocells Associated with Expansion Chain (with Wrap Around)	Max PT/ Macrocell
Chain-0	M0 Õ M4 Õ M8 Õ M12 Õ M0	75
Chain-1	M1 Õ M5 Õ M9 Õ M13 Õ M1	80
Chain-2	M2 Õ M6 Õ M10 Õ M14 Õ M2	75
Chain-3	M3 Õ M7 Õ M11 Õ M15 Õ M3	70

Every time the super cluster allocator is used, there is an incremental delay of t_{EXP}. When the super cluster allocator is used, all destinations other than the one being steered to, are given the value of ground (i.e., if the super cluster is steered to M (n+4), then M (n) is ground).

Macrocell

The 16 macrocells in the GLB are driven by the 16 outputs from the logic allocator. Each macrocell contains a programmable XOR gate, a programmable register/latch, along with routing for the logic and control functions. Figure 5 shows a graphical representation of the macrocell. The macrocells feed the ORP and GRP. A direct input from the I/O cell allows designers to use the macrocell to construct high-speed input registers. A programmable delay in this path allows designers to choose between the fastest possible set-up time and zero hold time.

Figure 5. Macrocell



Enhanced Clock Multiplexer

The clock input to the flip-flop can select any of the four block clocks along with the shared PT clock, and true and complement forms of the optional individual term clock. An 8:1 multiplexer structure is used to select the clock. The eight sources for the clock multiplexer are as follows:

- Block CLK0
- Block CLK1

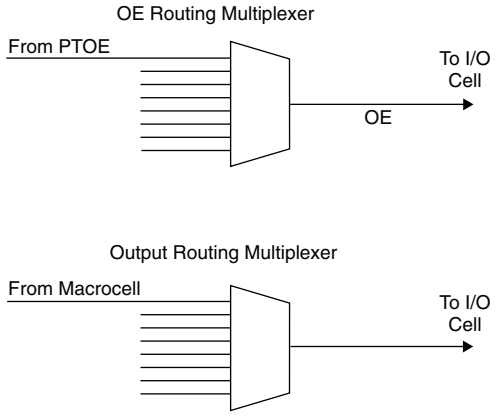
Output Routing Pool (ORP)

The Output Routing Pool allows macrocell outputs to be connected to any of several I/O cells within an I/O block. This provides greater flexibility in determining the pinout and allows design changes to occur without affecting the pinout. The output routing pool also provides a parallel capability for routing macrocell-level OE product terms. This allows the OE product term to follow the macrocell output as it is switched between I/O cells. The enhanced ORP of the ispMACH 4000ZE family consists of the following elements:

- Output Routing Multiplexers
- OE Routing Multiplexers

Figure 7 shows the structure of the ORP from the I/O cell perspective. This is referred to as an ORP slice. Each ORP has as many ORP slices as there are I/O cells in the corresponding I/O block.

Figure 7. ORP Slice



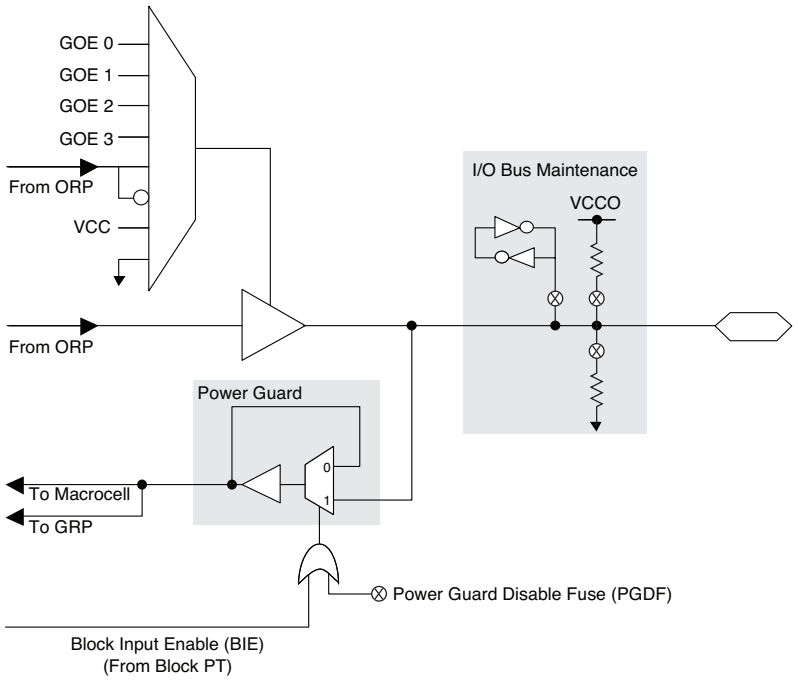
Output Routing Multiplexers

The details of connections between the macrocells and the I/O cells vary across devices and within a device dependent on the maximum number of I/Os available. Tables 5-7 provide the connection details.

Table 5. GLB/MC/ORP Combinations for ispMACH 4256ZE

GLB/MC	ORP Mux Input Macrocells
[GLB] [MC 0]	M0, M1, M2, M3, M4, M5, M6, M7
[GLB] [MC 1]	M2, M3, M4, M5, M6, M7, M8, M9
[GLB] [MC 2]	M4, M5, M6, M7, M8, M9, M10, M11
[GLB] [MC 3]	M6, M7, M8, M9, M10, M11, M12, M13
[GLB] [MC 4]	M8, M9, M10, M11, M12, M13, M14, M15
[GLB] [MC 5]	M10, M11, M12, M13, M14, M15, M0, M1
[GLB] [MC 6]	M12, M13, M14, M15, M0, M1, M2, M3
[GLB] [MC 7]	M14, M15, M0, M1, M2, M3, M4, M5

Figure 8. I/O Cell



Each output supports a variety of output standards dependent on the V_{CCO} supplied to its I/O bank. Outputs can also be configured for open drain operation. Each input can be programmed to support a variety of standards, independent of the V_{CCO} supplied to its I/O bank. The I/O standards supported are:

- LVTTL
- LVCMOS 3.3
- LVCMOS 2.5
- LVCMOS 1.8
- LVCMOS 1.5
- 3.3V PCI Compatible

All of the I/Os and dedicated inputs have the capability to provide a bus-keeper latch, pull-up resistor or pull-down resistor selectable on a “per-pin” basis. A fourth option is to provide none of these. The default in both hardware and software is such that when the device is erased or if the user does not specify, the input structure is configured to be a Pull-down Resistor.

Each ispMACH 4000ZE device I/O has an individually programmable output slew rate control bit. Each output can be individually configured for fast slew or slow slew. The typical edge rate difference between fast and slow slew setting is 20%. For high-speed designs with long, unterminated traces, the slow-slew rate will introduce fewer reflections, less noise and keep ground bounce to a minimum. For designs with short traces or well terminated lines, the fast slew rate can be used to achieve the highest speed.

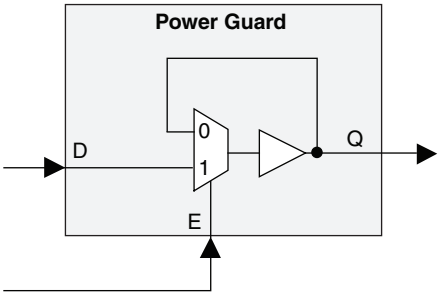
The ispMACH 4000ZE family has an always on, 200mV typical hysteresis for each input operational at 3.3V and 2.5V. This provides improved noise immunity for slow transitioning signals.

Power Guard

Power Guard allows easier achievement of standby current in the system. As shown in Figure 9, this feature consists of an enabling multiplexer between an I/O pin and input buffer, and its associated circuitry inside the device.

If the enable signal (E) is held low, all inputs (D) can be optionally isolated (guarded), such that, if any of these were toggled, it would not cause any toggle on internal pins (Q), thus, a toggling I/O pin will not cause any internal dynamic power consumption.

Figure 9. Power Guard



All the I/O pins in a block share a common Power Guard Enable signal. For a block of I/Os, this signal is called a Block Input Enable (BIE) signal. BIE can be internally generated using MC logic, or could come from external sources using one of the user I/O or input pins.

Any I/O pin in the block can be programmed to ignore the BIE signal. Thus, the feature can be enabled or disabled on a pin-by-pin basis.

Figure 10 shows Power Guard and BIE across multiple I/Os in a block that has eight I/Os.

Figure 10. Power Guard and BIE in a Block with 8 I/Os

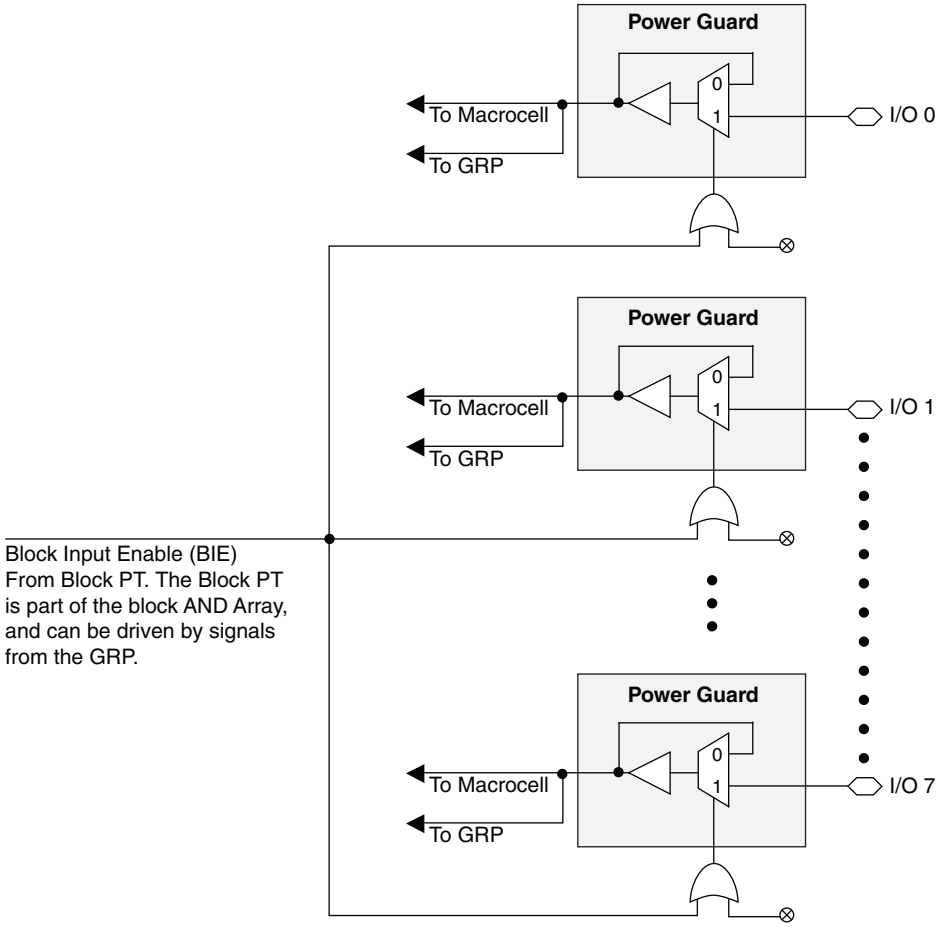


Table 12. OSC and TIMER MC Designation

Device	Macrocell	Block Number	MC Number
ispMACH 4032ZE	OSC MC TIMER MC	A B	15 15
ispMACH 4064ZE	OSC MC TIMER MC	A D	15 15
ispMACH 4128ZE	OSC MC TIMER MC	A G	15 15
ispMACH 4256ZE	OSC MC TIMER MC	C F	15 15

Zero Power/Low Power and Power Management

The ispMACH 4000ZE family is designed with high speed low power design techniques to offer both high speed and low power. With an advanced E^2 low power cell and non sense-amplifier design approach (full CMOS logic approach), the ispMACH 4000ZE family offers fast pin-to-pin speeds, while simultaneously delivering low standby power without needing any “turbo bits” or other power management schemes associated with a traditional sense-amplifier approach.

The zero power ispMACH 4000ZE is based on the 1.8V ispMACH 4000Z family. With innovative circuit design changes, the ispMACH 4000ZE family is able to achieve the industry’s lowest static power.

IEEE 1149.1-Compliant Boundary Scan Testability

All ispMACH 4000ZE devices have boundary scan cells and are compliant to the IEEE 1149.1 standard. This allows functional testing of the circuit board on which the device is mounted through a serial scan path that can access all critical logic notes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test node data to be captured and shifted out for verification. In addition, these devices can be linked into a board-level serial scan path for more board-level testing. The test access port operates with an LVCMOS interface that corresponds to the power supply voltage.

I/O Quick Configuration

To facilitate the most efficient board test, the physical nature of the I/O cells must be set before running any continuity tests. As these tests are fast, by nature, the overhead and time that is required for configuration of the I/Os’ physical nature should be minimal so that board test time is minimized. The ispMACH 4000ZE family of devices allows this by offering the user the ability to quickly configure the physical nature of the I/O cells. This quick configuration takes milliseconds to complete, whereas it takes seconds for the entire device to be programmed. Lattice's ispVM™ System programming software can either perform the quick configuration through the PC parallel port, or can generate the ATE or test vectors necessary for a third-party test system.

IEEE 1532-Compliant In-System Programming

Programming devices in-system provides a number of significant benefits including: rapid prototyping, lower inventory levels, higher quality and the ability to make in-field modifications. All ispMACH 4000ZE devices provide In-System Programming (ISP™) capability through the Boundary Scan Test Access Port. This capability has been implemented in a manner that ensures that the port remains complaint to the IEEE 1149.1 standard. By using IEEE 1149.1 as the communication interface through which ISP is achieved, users get the benefit of a standard, well-defined interface. All ispMACH 4000ZE devices are also compliant with the IEEE 1532 standard.

The ispMACH 4000ZE devices can be programmed across the commercial temperature and voltage range. The PC-based Lattice software facilitates in-system programming of ispMACH 4000ZE devices. The software takes the JEDEC file output produced by the design implementation software, along with information about the scan chain, and creates a set of vectors used to drive the scan chain. The software can use these vectors to drive a scan chain via the parallel port of a PC. Alternatively, the software can output files in formats understood by common auto-

mated test equipment. This equipment can then be used to program ispMACH 4000ZE devices during the testing of a circuit board.

User Electronic Signature

The User Electronic Signature (UES) allows the designer to include identification bits or serial numbers inside the device, stored in E^2CMOS memory. The ispMACH 4000ZE device contains 32 UES bits that can be configured by the user to store unique data such as ID codes, revision numbers or inventory control codes.

Security Bit

A programmable security bit is provided on the ispMACH 4000ZE devices as a deterrent to unauthorized copying of the array configuration patterns. Once programmed, this bit defeats readback of the programmed pattern by a device programmer, securing proprietary designs from competitors. Programming and verification are also defeated by the security bit. The bit can only be reset by erasing the entire device.

Hot Socketing

The ispMACH 4000ZE devices are well-suited for applications that require hot socketing capability. Hot socketing a device requires that the device, during power-up and down, can tolerate active signals on the I/Os and inputs without being damaged. Additionally, it requires that the effects of I/O pin loading be minimal on active signals. The ispMACH 4000ZE devices provide this capability for input voltages in the range 0V to 3.0V.

Density Migration

The ispMACH 4000ZE family has been designed to ensure that different density devices in the same package have the same pin-out. Furthermore, the architecture ensures a high success rate when performing design migration from lower density parts to higher density parts. In many cases, it is possible to shift a lower utilization design targeted for a high density device to a lower density device. However, the exact details of the final resource utilization will impact the likely success in each case.

I/O Recommended Operating Conditions

Standard	V_{CCO} (V)[1]	
	Min.	Max.
LVTTL	3.0	3.6
LVCMOS 3.3	3.0	3.6
Extended LVCMOS 3.3	2.7	3.6
LVCMOS 2.5	2.3	2.7
LVCMOS 1.8	1.65	1.95
LVCMOS 1.5	1.4	1.6
PCI 3.3	3.0	3.6

1. Typical values for V_{CCO} are the average of the min. and max. values.

DC Electrical Characteristics

Over Recommended Operating Conditions

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
I_{IL}, I_{IH}[1, 2]	Input Leakage Current	$0 \le V_{IN} < V_{CCO}$	—	0.5	1	µA
I_{IH}[1]	Input High Leakage Current	$V_{CCO} < V_{IN} \le 5.5V$	—	—	10	µA
I_{PU}	I/O Weak Pull-up Resistor Current	$0 \le V_{IN} \le 0.7V_{CCO}$	-20	—	-150	µA
I_{PD}	I/O Weak Pull-down Resistor Current	V_{IL} (MAX) $\le V_{IN} \le V_{IH}$ (MAX)	30	—	150	µA
I_{BHLS}	Bus Hold Low Sustaining Current	$V_{IN} = V_{IL}$ (MAX)	30	—	—	µA
I_{BHHS}	Bus Hold High Sustaining Current	$V_{IN} = 0.7\ V_{CCO}$	-20	—	—	µA
I_{BHLO}	Bus Hold Low Overdrive Current	$0V \le V_{IN} \le V_{BHT}$	—	—	150	µA
I_{BHHO}	Bus Hold High Overdrive Current	$V_{BHT} \le V_{IN} \le V_{CCO}$	—	—	-150	µA
V_{BHT}	Bus Hold Trip Points	—	V_{CCO} * 0.35	—	V_{CCO} * 0.65	V
C_1	I/O Capacitance[3]	V_{CCO} = 3.3V, 2.5V, 1.8V, 1.5V	—	8	—	pf
		V_{CC} = 1.8V, V_{IO} = 0 to V_{IH} (MAX)	—		—	
C_2	Clock Capacitance[3]	V_{CCO} = 3.3V, 2.5V, 1.8V, 1.5V	—	6	—	pf
		V_{CC} = 1.8V, V_{IO} = 0 to V_{IH} (MAX)	—		—	
C_3	Global Input Capacitance[3]	V_{CCO} = 3.3V, 2.5V, 1.8V, 1.5V	—	6	—	pf
		V_{CC} = 1.8V, V_{IO} = 0 to V_{IH} (MAX)	—		—	

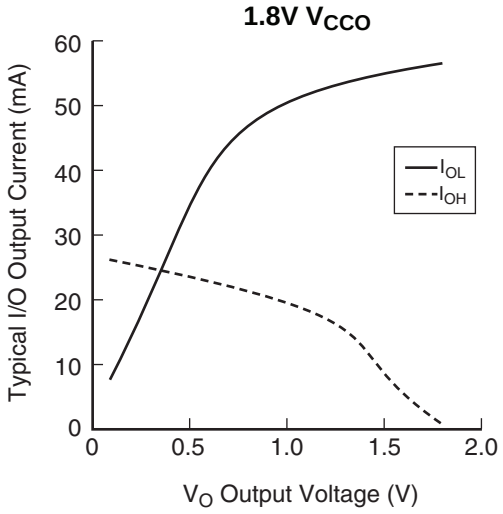
1. Input or I/O leakage current is measured with the pin configured as an input or as an I/O with the output driver tristated. It is not measured with the output driver active. Bus maintenance circuits are disabled.
2. I_{IH} excursions of up to 1.5µA maximum per pin above the spec limit may be observed for certain voltage conditions on no more than 10% of the device's I/O pins.
3. Measured T_A = 25°C, f = 1.0MHz.

I/O DC Electrical Characteristics

Over Recommended Operating Conditions

Standard	V_{IL}		V_{IH}		V_{OL} Max (V)	V_{OH} Min (V)	I_{OL}[1] (mA)	I_{OH}[1] (mA)
	Min (V)	Max (V)	Min (V)	Max (V)				
LVTTL	-0.3	0.80	2.0	5.5	0.40	V_{CCO} - 0.40	8.0	-4.0
					0.20	V_{CCO} - 0.20	0.1	-0.1
LVCMOS 3.3	-0.3	0.80	2.0	5.5	0.40	V_{CCO} - 0.40	8.0	-4.0
					0.20	V_{CCO} - 0.20	0.1	-0.1
LVCMOS 2.5	-0.3	0.70	1.70	3.6	0.40	V_{CCO} - 0.40	8.0	-4.0
					0.20	V_{CCO} - 0.20	0.1	-0.1
LVCMOS 1.8	-0.3	0.35 * V_{CC}	0.65 * V_{CC}	3.6	0.40	V_{CCO} - 0.45	2.0	-2.0
					0.20	V_{CCO} - 0.20	0.1	-0.1
LVCMOS 1.5[2]	-0.3	0.35 * V_{CC}	0.65 * V_{CC}	3.6	0.40	V_{CCO} - 0.45	2.0	-2.0
					0.20	V_{CCO} - 0.20	0.1	-0.1
PCI 3.3	-0.3	0.3 * 3.3 * (V_{CC} / 1.8)	0.5 * 3.3 * (V_{CC} / 1.8)	5.5	0.1 V_{CCO}	0.9 V_{CCO}	1.5	-0.5

1. The average DC current drawn by I/Os between adjacent bank GND connections, or between the last GND in an I/O bank and the end of the I/O bank, as shown in the logic signals connection table, shall not exceed *n**8mA. Where *n* is the number of I/Os between bank GND connections or between the last GND in a bank and the end of a bank.
2. For 1.5V inputs, there may be an additional DC current drawn from V_{CC}, if the ispMACH 4000ZE V_{CC} and the V_{CC} of the driving device (V_{CC}d-d; that determines steady state V_{IH}) are in the extreme range of their specifications. Typically, DC current drawn from V_{CC} will be 2µA per input.



ispMACH 4000ZE Internal Timing Parameters (Cont.)

Over Recommended Operating Conditions

Parameter	Description		LC4032ZE -4 Min.	LC4032ZE -4 Max.	LC4064ZE -4 Min.	LC4064ZE -4 Max.	Units
LVCMOS15_out	Output Configured as 1.5V Buffer	t_{EN}, t_{DIS}, t_{BUF}	—	0.20	—	0.20	ns
LVCMOS18_out	Output Configured as 1.8V Buffer	t_{EN}, t_{DIS}, t_{BUF}	—	0.00	—	0.00	ns
LVCMOS25_out	Output Configured as 2.5V Buffer	t_{EN}, t_{DIS}, t_{BUF}	—	0.10	—	0.10	ns
LVCMOS33_out	Output Configured as 3.3V Buffer	t_{EN}, t_{DIS}, t_{BUF}	—	0.20	—	0.20	ns
PCI_out	Output Configured as PCI Compatible Buffer	t_{EN}, t_{DIS}, t_{BUF}	—	0.20	—	0.20	ns
Slow Slew	Output Configured for Slow Slew Rate	t_{EN}, t_{BUF}	—	1.00	—	1.00	ns

Note: Internal Timing Parameters are not tested and are for reference only. Refer to the timing model in this data sheet for further details.
Timing v.0.8

ispMACH 4000ZE Internal Timing Parameters (Cont.)

Over Recommended Operating Conditions

Parameter	Description	All Devices				Units
		-5		-7		
		Min.	Max.	Min.	Max.	
In/Out Delays						
t_{IN}	Input Buffer Delay	—	1.05	—	1.90	ns
t_{GCLK_IN}	Global Clock Input Buffer Delay	—	1.95	—	2.15	ns
t_{GOE}	Global OE Pin Delay	—	3.00	—	4.30	ns
t_{BUF}	Delay through Output Buffer	—	1.10	—	1.30	ns
t_{EN}	Output Enable Time	—	2.50	—	2.70	ns
t_{DIS}	Output Disable Time	—	2.50	—	2.70	ns
t_{PGSU}	Input Power Guard Setup Time	—	4.30	—	5.60	ns
t_{PGH}	Input Power Guard Hold Time	—	0.00	—	0.00	ns
t_{PGPW}	Input Power Guard BIE Minimum Pulse Width	—	6.00	—	8.00	ns
t_{PGRT}	Input Power Guard Recovery Time Following BIE Dis-sertation	—	5.00	—	7.00	ns
Routing Delays						
t_{ROUTE}	Delay through GRP	—	2.25	—	2.50	ns
t_{PDi}	Macrocell Propagation Delay	—	0.45	—	0.50	ns
t_{MCELL}	Macrocell Delay	—	0.65	—	1.00	ns
t_{INREG}	Input Buffer to Macrocell Register Delay	—	1.00	—	1.00	ns
t_{FBK}	Internal Feedback Delay	—	0.75	—	0.30	ns
t_{ORP}	Output Routing Pool Delay	—	0.30	—	0.30	ns
Register/Latch Delays						
t_S	D-Register Setup Time (Global Clock)	0.90	—	1.25	—	ns
t_{S_PT}	D-Register Setup Time (Product Term Clock)	2.00	—	2.35	—	ns
t_H	D-Register Hold Time	2.00	—	3.25	—	ns
t_{ST}	T-Register Setup Time (Global Clock)	1.10	—	1.45	—	ns
t_{ST_PT}	T-register Setup Time (Product Term Clock)	2.20	—	2.65	—	ns
t_{HT}	T-Resister Hold Time	2.00	—	3.25	—	ns
t_{SIR}	D-Input Register Setup Time (Global Clock)	1.20	—	0.65	—	ns
t_{SIR_PT}	D-Input Register Setup Time (Product Term Clock)	1.45	—	1.45	—	ns
t_{HIR}	D-Input Register Hold Time (Global Clock)	1.40	—	2.05	—	ns
t_{HIR_PT}	D-Input Register Hold Time (Product Term Clock)	1.10	—	1.20	—	ns
t_{COi}	Register Clock to Output/Feedback MUX Time	—	0.45	—	0.75	ns
t_{CES}	Clock Enable Setup Time	2.00	—	2.00	—	ns
t_{CEH}	Clock Enable Hold Time	0.00	—	0.00	—	ns
t_{SL}	Latch Setup Time (Global Clock)	0.90	—	1.55	—	ns
t_{SL_PT}	Latch Setup Time (Product Term Clock)	2.00	—	2.05	—	ns
t_{HL}	Latch Hold Time	2.00	—	1.17	—	ns
t_{GOi}	Latch Gate to Output/Feedback MUX Time	—	0.35	—	0.33	ns
t_{PDLi}	Propagation Delay through Transparent Latch to Output/ Feedback MUX	—	0.25	—	0.25	ns
t_{SRi}	Asynchronous Reset or Set to Output/Feedback MUX Delay	—	0.95	—	0.28	ns

ispMACH 4000ZE Power Supply and NC Connections[1]

Signal	48 TQFP[2]	64 csBGA[3, 4]	64 ucBGA[3, 4]	100 TQFP[2]
VCC	12, 36	E4, D5	E4, D5	25, 40, 75, 90
VCCO0 VCCO (Bank 0)	6	**4032ZE:** E3 **4064ZE:** E3, F4	C3, F3	13, 33, 95
VCCO1 VCCO (Bank 1)	30	**4032ZE:** D6 **4064ZE:** D6, C6	F6, A6	45, 63, 83
GND	13, 37	D4, E5	D4, D5	1, 26, 51, 76
GND (Bank 0)	5	D4, E5	D4, D5	7, 18, 32, 96
GND (Bank 1)	29	D4, E5	D4, D5	46, 57, 68, 82
NC	—	—	—	—

1. All grounds must be electrically connected at the board level. However, for the purposes of I/O current loading, grounds are associated with the bank shown.
2. Pin orientation follows the conventional order from pin 1 marking of the top side view and counter-clockwise.
3. Pin orientation A1 starts from the upper left corner of the top side view with alphabetical order ascending vertically and numerical order ascending horizontally.
4. All bonded grounds are connected to the following two balls, D4 and E5.

ispMACH 4000ZE Power Supply and NC Connections[1] (Cont.)

Signal	132 ucBGA[3]	144 csBGA[3]	144 TQFP[2]
VCC	M1, M7, A12, B5	H5, H8, E8, E5	36, 57, 108, 129
VCCO0 VCCO (Bank 0)	B1, H4, L2, J5, A4	E4, F4, G4, J5, D5	3, 19, 34, 47, 136
VCCO1 VCCO (Bank 1)	K9, L12, F12, D9, C7	J8, H9, G9, F9, D8	64, 75, 91, 106, 119
GND	E5, E8, H5, H8	F6, G6, G7, F7	1, 37, 73, 109
GND (Bank 0)	E2, H2, M4, B7, B3	G5, H4, H6, E6, F5	10, 18[4], 27, 46, 127, 137
GND (Bank 1)	L7, J9, H12, E9, A9	H7, J9, G8, F8, E7	55, 65, 82, 90[4], 99, 118
NC	—	**4064ZE:** E4, B2, B1, D2, D3, E1, H1, H3, H2, L1, G4, M1, K3, M2, M4, L5, H7, L8, M8, L10, K9, M11, H9, L12, L11, J12, J11, H10, D10, F10, D12, B12, F9, A12, C10, B10, A9, B8, E6, B5, A5, C4, B3, A2 **4128ZE:** D2, D3, H2, M1, K3, M11, J12, J11, D12, A12, C10, A2	**4128ZE:** 17, 20, 38, 45, 72, 89, 92, 110, 117, 144 **4256ZE:** 18, 90

1. All grounds must be electrically connected at the board level. However, for the purposes of I/O current loading, grounds are associated with the bank shown.
2. Pin orientation follows the conventional order from pin 1 marking of the top side view and counter-clockwise.
3. Pin orientation A1 starts from the upper left corner of the top side view with alphabetical order ascending vertically and numerical order ascending horizontally.
4. For the LC4256ZE, pins 18 and 90 are no connects.

ispMACH 4032ZE and 4064ZE Logic Signal Connections: 64 csBGA (Cont.)

Ball Number	Bank Number	ispMACH 4032ZE	ispMACH 4064ZE
		GLB/MC/Pad	GLB/MC/Pad
E7	1	NC	D14
E6	1	B9	D13
D7	1	B10	D12
D8	1	NC	D11
C5	1	NC	D10
C7	1	B11	D9
C8	1	NC	D8
B8	-	TDO	TDO
D5	-	VCC	VCC
GND*	-	GND	GND
A8	1	B12	D7
A7	1	NC	D6
B7	1	NC	D5
A6	1	B13	D4
GND*	1	NC	GND (Bank 1)
C6	1	NC	VCCO (Bank 1)
B6	1	B14	D3
A5	1	NC	D2
B5	1	B15/GOE1	D0/GOE1
A4	1	CLK3/I	CLK3/I
C4	0	CLK0/I	CLK0/I
B4	0	A0/GOE0	A0/GOE0
B3	0	A1	A1
A3	0	A2	A2
A2	0	A3	A4
A1	0	A4	A6

* All bonded grounds are connected to the following two balls, D4 and E5.

ispMACH 4064ZE Logic Signal Connections: 64 ucBGA (Cont.)

Ball Number	Bank Number	GLB/MC/Pad
E7	1	D13
E6	1	D12
D8	1	D11
D7	1	D10
D6	1	D9
C8	1	D8
C7	-	TDO
D5	-	VCC
GND*	-	GND
B8	1	D7
A8	1	D6
B7	1	D5
A7	1	D4
GND*	1	GND (Bank 1)
A6	1	VCCO (Bank 1)
B6	1	D3
C6	1	D2
A5	1	D0/GOE1
B5	1	CLK3/I
C5	0	CLK0/I
A4	0	A0/GOE0
B4	0	A1
C4	0	A2
A3	0	A4
A2	0	A6

* All bonded grounds are connected to the following two balls, D4 and E5.

ispMACH 4128ZE Logic Signal Connections: 132 ucBGA (Cont.)

Ball Number	Bank Number	GLB/MC/Pad
A2	0	A14

* All bonded core grounds are connected to the following four balls, E5, E8, H5 and H8.

ispMACH 4064ZE, 4128ZE and 4256ZE Logic Signal Connections: 144 csBGA (Cont.)

Ball Number	Bank Number	LC4064ZE	LC4128ZE	LC4256ZE
		GLB/MC/Pad	GLB/MC/Pad	GLB/MC/Pad
J12	1	NC Ball	NC Ball	L14
J11	1	NC Ball	NC Ball	L12
H10	1	NC Ball	F8	L10
H12	1	C12	F9	L8
G11	1	C13	F10	L6
H11	1	C14	F12	L4
G12	1	C15	F13	L2
G10*	1	I	F14	L0
G9	1	VCCO (Bank 1)	VCCO (Bank 1)	VCCO (Bank 1)
F12	1	D15	G14	M0
F11	1	D14	G13	M2
E11	1	D13	G12	M4
E12	1	D12	G10	M6
D10	1	NC Ball	G9	M8
F10	1	NC Ball	G8	M10
D12	1	NC Ball	NC Ball	M12
F8	1	GND (Bank 1)	GND (Bank 1)	GND (Bank 1)
E10	1	D11	G6	N2
D11	1	D10	G5	N4
E9	1	D9	G4	N6
C12	1	D8	G2	N8
C11*	1	I	G1	N10
B12	1	NC Ball	G0	N12
F9	1	NC Ball	VCCO (Bank 1)	VCCO (Bank 1)
B11	-	TDO	TDO	TDO
E8	-	VCC	VCC	VCC
F7	-	GND	GND	GND
A12	1	NC Ball	NC Ball	O14
C10	1	NC Ball	NC Ball	O12
B10	1	NC Ball	H14	O10
A11*	1	I	H13	O8
D9	1	D7	H12	O6
B9	1	D6	H10	O4
C9	1	D5	H9	O2
A10	1	D4	H8	O0
E7	1	GND (Bank 1)	GND (Bank 1)	GND (Bank 1)
D8	1	VCCO (Bank 1)	VCCO (Bank 1)	VCCO (Bank 1)
A9	1	NC Ball	H6	P12
B8	1	NC Ball	H5	P10
C8	1	D3	H4	P8
A8	1	D2	H2	P6
D7	1	D1	H1	P4
B7	1	D0/GOE1	H0/GOE1	P2/GOE1

ispMACH 4128ZE and 4256ZE Logic Signal Connections: 144 TQFP (Cont.)

Pin Number	Bank Number	LC4128ZE	LC4256ZE
		GLB/MC/Pad	GLB/MC/Pad
86	1	F12	L8
87	1	F13	L6
88	1	F14	L4
89*	1	NC	I
90	1	GND (Bank 1)	NC
91	1	VCCO (Bank 1)	VCCO (Bank 1)
92*	1	NC	I
93	1	G14	M2
94	1	G13	M4
95	1	G12	M6
96	1	G10	M8
97	1	G9	M10
98	1	G8	M12
99	1	GND (Bank 1)	GND (Bank 1)
100	1	G6	N2
101	1	G5	N4
102	1	G4	N6
103	1	G2	N8
104	1	G1	N10
105	1	G0	N12
106	1	VCCO (Bank 1)	VCCO (Bank 1)
107	-	TDO	TDO
108	-	VCC	VCC
109	-	GND	GND
110*	1	NC	I
111	1	H14	O12
112	1	H13	O10
113	1	H12	O8
114	1	H10	O6
115	1	H9	O4
116	1	H8	O2
117*	1	NC	I
118	1	GND (Bank 1)	GND (Bank 1)
119	1	VCCO (Bank 1)	VCCO (Bank 1)
120	1	H6	P12
121	1	H5	P10
122	1	H4	P8
123	1	H2	P6
124	1	H1	P4
125	1	H0/GOE1	P2/GOE1
126	1	CLK3/I	CLK3/I
127	0	GND (Bank 0)	GND (Bank 0)
128	0	CLK0/I	CLK0/I

ispMACH 4128ZE and 4256ZE Logic Signal Connections: 144 TQFP (Cont.)

Pin Number	Bank Number	LC4128ZE	LC4256ZE
		GLB/MC/Pad	GLB/MC/Pad
129	-	VCC	VCC
130	0	A0/GOE0	A2/GOE0
131	0	A1	A4
132	0	A2	A6
133	0	A4	A8
134	0	A5	A10
135	0	A6	A12
136	0	VCCO (Bank 0)	VCCO (Bank 0)
137	0	GND (Bank 0)	GND (Bank 0)
138	0	A8	B2
139	0	A9	B4
140	0	A10	B6
141	0	A12	B8
142	0	A13	B10
143	0	A14	B12
144*	0	NC	I

* This pin is input only for the LC4256ZE.

Revision History

Date	Version	Change Summary
April 2008	01.0	Initial release.
July 2008	01.1	Updated Features bullets.
		Updated typical Hysteresis voltage.
		Updated Power Guard for Dedicated Inputs section.
		Updated DC Electrical Characteristics table.
		Updated Supply Current table.
		Updated I/O DC Electrical Characteristics table and note 2.
		Updated ispMACH 4000ZE Timing Model.
		Added new parameters for the Internal Oscillator.
		Updated ORP Reference table.
		Updated Power Supply and NC Connections table.
		Updated 100 TQFP Logic Signal Connections table with LC4128ZE and 4256ZE.
		Updated 144 csBGA Logic Signal Connections table with LC4128ZE and 4256ZE.
		Added 144 TQFP Logic Signal Connections table.
August 2008	01.2	Data sheet status changed from advance to final.
		Updated Supply Current table.
		Updated External Switching Characteristics.
		Updated Internal Timing Parameters.
		Updated Power Consumption graph and Power Estimation Coefficients table.
		Updated Ordering Information mark format example.
December 2008	01.3	Updated ispMACH 4000ZE Family Selection Guide table to include 64-ball ucBGA and 132-ball ucBGA packages.
		Updated ispMACH 4000ZE Power Supply and NC Connections table to include 64-ball ucBGA and 132-ball ucBGA packages.
		Added Logic Signal Connections tables for 64-ball ucBGA and 132-ball ucBGA packages.
		Updated Part Number Description diagram for 64-ball ucBGA and 132-ball ucBGA packages.
		Updated Ordering Information tables for 64-ball ucBGA and 132-ball ucBGA packages.
May 2009	01.4	Correction to t_{CW}, t_{GW}, t_{WIR} and f_{MAX} parameters in External Switching Characteristics table.
June 2011	01.5	Added copper bond package part numbers.
		Added footnote 4 to Absolute Maximum Ratings.
February 2012	01.6	Updated document with new corporate logo.
February 2012	01.7	Removed copper bond packaging information. Refer to PCN 04A-12 for further information.
		Updated topside marks with new logos in the Ordering Information section.